DATE Best Paper Awards

Each year the Design, Automation and Test in Europe Conference presents awards to the authors of the best papers. The selection is performed by an award committee, based on the results of the reviewing process and the quality of the final paper.

The **DATE 2014** best papers are:

D Track

MAY-HAPPEN-IN-PARALLEL ANALYSIS BASED ON SEGMENT GRAPHS FOR SAFE ESL MODELS

Weiwei Chen, Xu Han, Rainer Dömer,
Center for Embedded Computer Systems, University of California, Irvine, USA

A Track

AN EFFICIENT RELIABLE PUF-BASED CRYPTOGRAPHIC KEY GENERATOR IN 65NM CMOS

Mudit Bhargava, Ken Mai,
Department of Electrical and Computer Engineering, Carnegie Mellon University, USA

T Track:

EFFICIENT SMT-BASED ATPG FOR INTERCONNECT OPEN DEFECTS

Dominik Erb, Karsten Scheibler, Matthias Sauer, Bernd Becker,
University of Freiburg, Germany

E Track

SCALABILITY BOTTLENECKS DISCOVERY IN MPSOC PLATFORMS USING DATA MINING ON SIMULATION TRACES

Sofiane Lagraa[1,2], Alexandre Termier[1] and Frédéric Pétrot[2]
[1]LIG Laboratory, University Joseph Fourier, Grenoble, France;
[2]TIMA Laboratory, Grenoble Institute of Technology, Grenoble, France

Congratulations to the winners!